

Application No.	Applicant(s)
09/752,046	SCHIER, JOHN ELMORE
Examiner	Art Unit
Christopher A. Boyek	2121

SEARCHED					
Class	Subclass	Date	Examiner		
713	150, 268, 175, 176, 200-202	11/23/2004	CR		
709	204, 206	11/23/2004	CR		
705	50, 56	11/23/2004	CR		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
BRS Text Search USPAT, USOCR, DERWENT, JPO, EPO, IBM TDB, US PGPUB	11/23/2004	CR
DIALOG Text Search COMPSCI, ELECTRON, SOFTWARE	11/23/2004	CR
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